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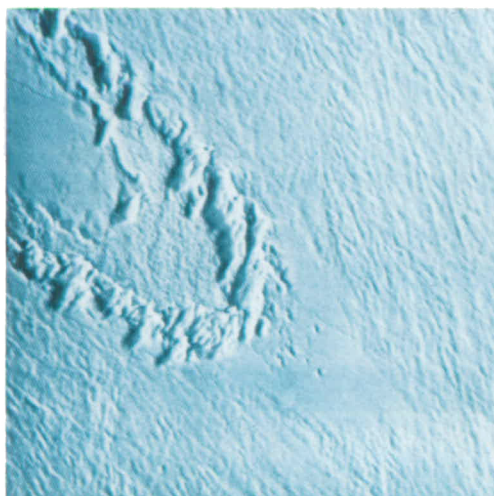
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ON THE COVER: False-color multiple Auger image of a reaction zone between a SiC fiber and a Ti alloy matrix shown in the SEM micrograph at the left. The false-color image was created from a multispectral scanning electron microscope Auger image by simultaneously collecting the three regions of the secondary electron spectrum corresponding to Auger transitions due to Ti, Si, and C. These three intensities were displayed as a scatter diagram, and the regions corresponding to elemental correlations were colored. The color image therefore shows not Auger intensities, but elemental associations: yellow-gold corresponds to the Ti matrix, blue to Ti₂Si₃, red to TiC, purple to SiC, and rust plus green to carbon contamination. These techniques are discussed in "New Directions in Auger Microanalysis" by R. Browning in this issue. Photo courtesy of R. Browning.

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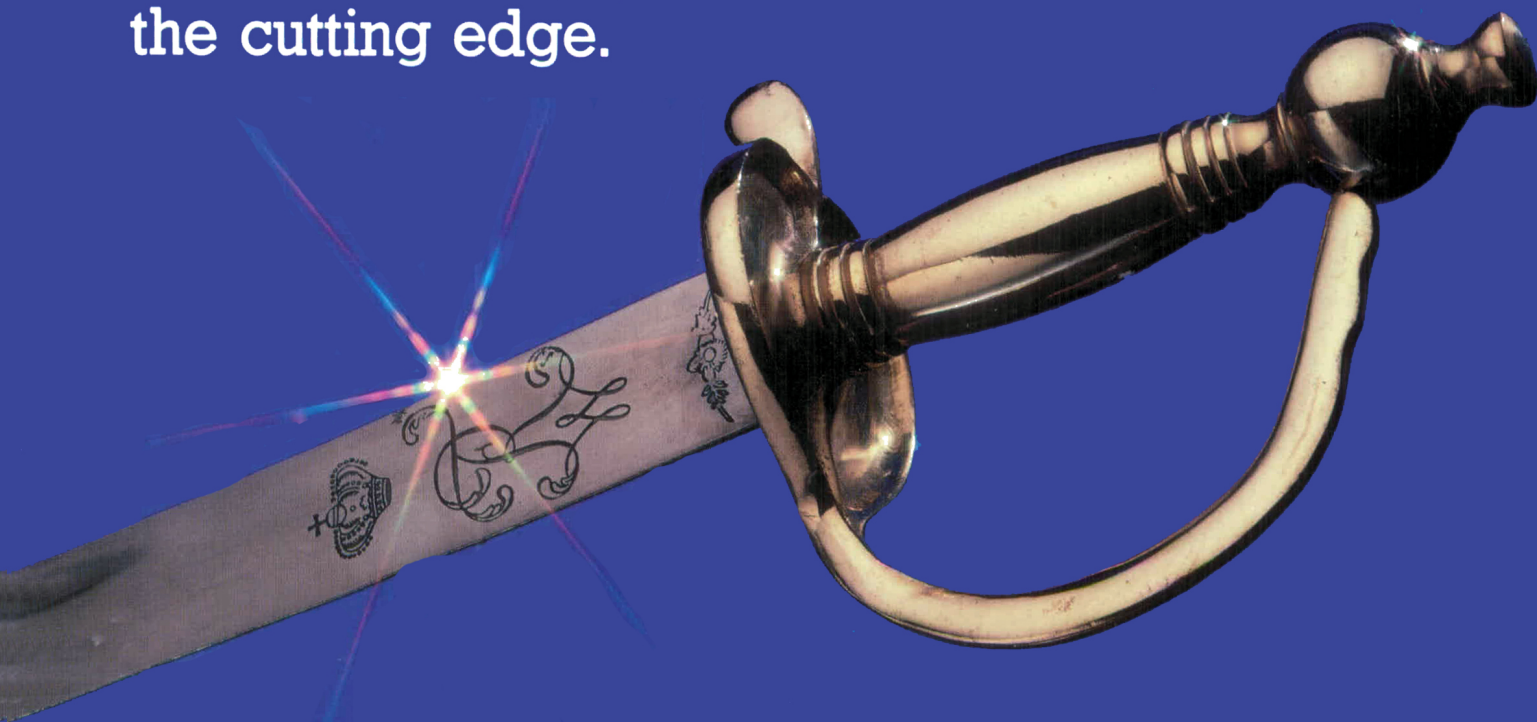
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